

RoHS Compliant Product
A suffix of "C" specifies halogen & lead-free

DESCRIPTION

These miniature surface mount MOSFETs utilize a high cell density trench process to provide low R_{DS(on)} and to ensure minimal power loss and heat dissipation.

FEATURES

- Low R_{DS(on)} provides higher efficiency and extends battery life.
- Low thermal impedance copper leadframe SC-59 saves board space.
- Fast switching speed.
- High performance trench technology.

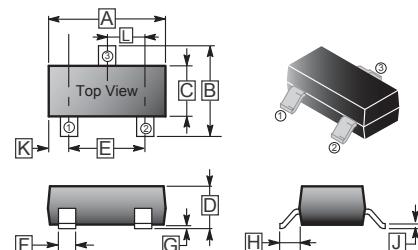
APPLICATION

DC-DC converters and power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

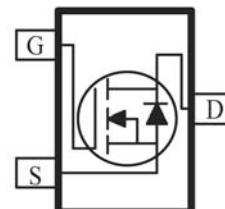
PACKAGE INFORMATION

Package	MPQ	Leader Size
SC-59	3K	7' inch

SC-59



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	2.70	3.10	G	0.10	REF.
B	2.25	3.00	H	0.40	REF.
C	1.30	1.70	J	0.10	0.20
D	1.00	1.40	K	0.45	0.55
E	1.70	2.30	L	0.85	1.15
F	0.35	0.50			



ABSOLUTE MAXIMUM RATINGS (T_A=25°C unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±12	V
Continuous Drain Current ¹	I _D	5.3	A
		4.1	
Pulsed Drain Current ²	I _{DM}	30	A
Continuous Source Current (Diode Conduction) ¹	I _S	1.9	A
Power Dissipation ¹	P _D	1.3	W
		0.8	
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 ~ 150	°C
Thermal Resistance Rating			
Maximum Junction to Ambient ¹	t ≤ 10 sec	100	°C/W
	Steady-State	166	

Notes:

1. Surface Mounted on 1" x 1" FR4 Board.
2. Pulse width limited by maximum junction temperature.

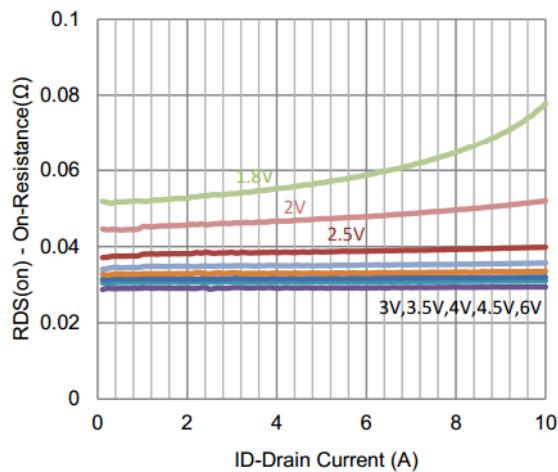
ELECTRICAL CHARACTERISTICS (T_A=25°C unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Static						
Gate-Threshold Voltage	V _{GS(th)}	0.4	-	-	V	V _{DS} =V _{GS} , I _D =250µA
Gate-Body Leakage	I _{GSS}	-	-	±100	nA	V _{DS} =0, V _{GS} =±12V
Zero Gate Voltage Drain Current	I _{DSS}	-	-	1	µA	V _{DS} =24V, V _{GS} =0
		-	-	25		V _{DS} =24V, V _{GS} =0, T _J =55°C
On-State Drain Current ¹	I _{D(ON)}	5	-	-	A	V _{DS} =5V, V _{GS} =4.5V
Drain-Source On-Resistance ¹	R _{DS(ON)}	-	-	32	mΩ	V _{GS} =4.5V, I _D =4.1A
		-	-	64		V _{GS} =2.5V, I _D =3.3A
Forward Transconductance ¹	g _{FS}	-	8	-	S	V _{DS} =15V, I _D =4.1A
Diode Forward Voltage	V _{SD}	-	0.68	-	V	I _S =9A, V _{GS} =0
Dynamic ²						
Total Gate Charge	Q _g	-	8	-	nC	I _D =4.1A V _{DS} =15V V _{GS} =4.5V
Gate-Source Charge	Q _{gs}	-	1.1	-		
Gate-Drain Charge	Q _{gd}	-	3.4	-		
Input Capacitance	C _{iss}	-	449	-	pF	V _{DS} =15V, V _{GS} =0, f=1MHz
Output Capacitance	C _{oss}	-	70	-		
Reverse Transfer Capacitance	C _{rss}	-	56	-		
Turn-On Delay Time	T _{d(ON)}	-	7	-	nS	I _D = 4.1A, V _{DS} =15V V _{GEN} =4.5V R _L =3.7Ω R _{GEN} =6Ω
Rise Time	T _r	-	15	-		
Turn-Off Delay Time	T _{d(OFF)}	-	37	-		
Fall Time	T _f	-	11	-		

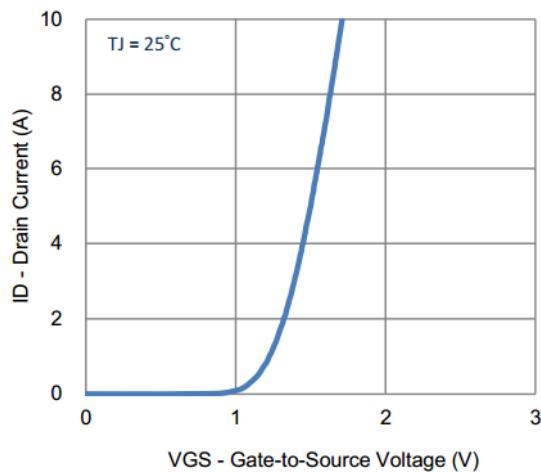
Notes:

1. Pulse test : PW ≤ 300 us duty cycle ≤ 2%.
2. Guaranteed by design, not subject to production testing.

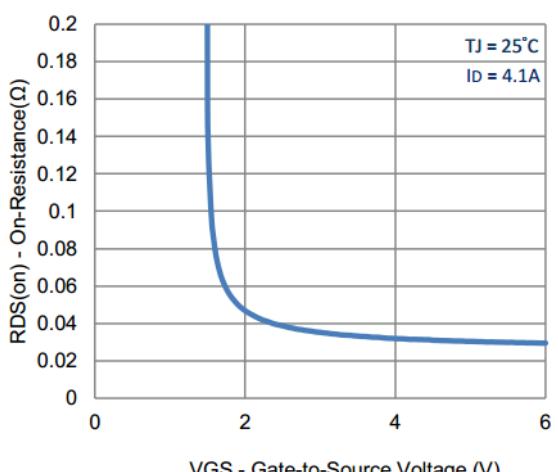
CHARACTERISTIC CURVES



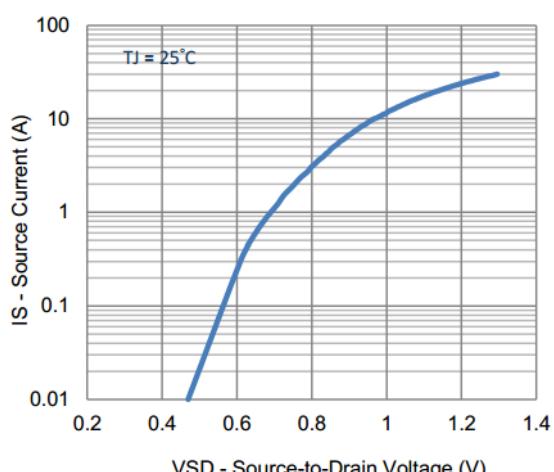
1. On-Resistance vs. Drain Current



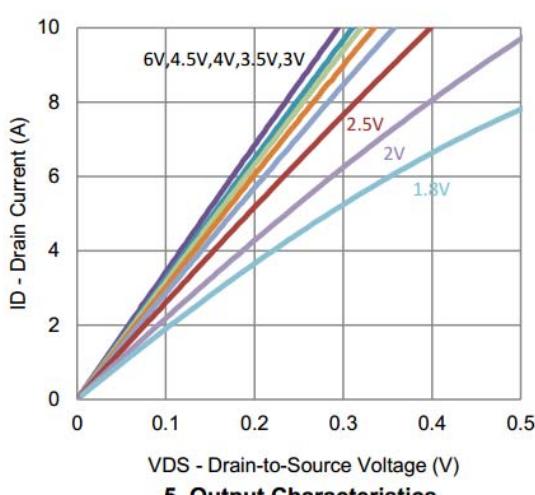
2. Transfer Characteristics



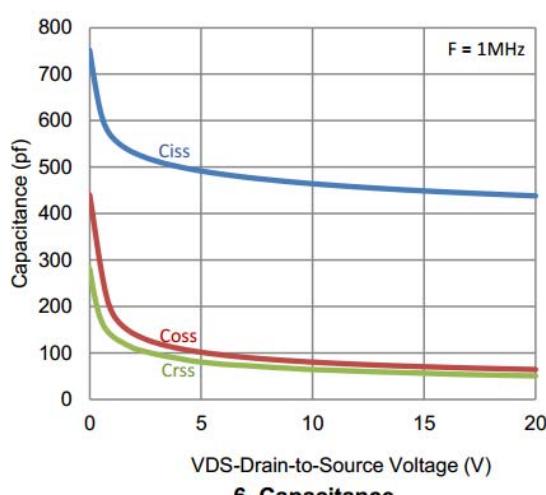
3. On-Resistance vs. Gate-to-Source Voltage



4. Drain-to-Source Forward Voltage

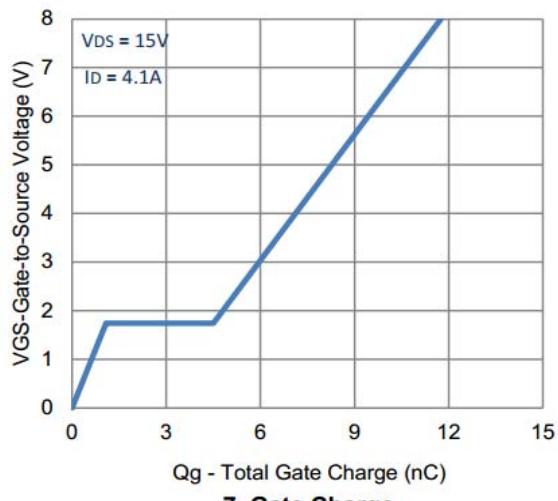


5. Output Characteristics

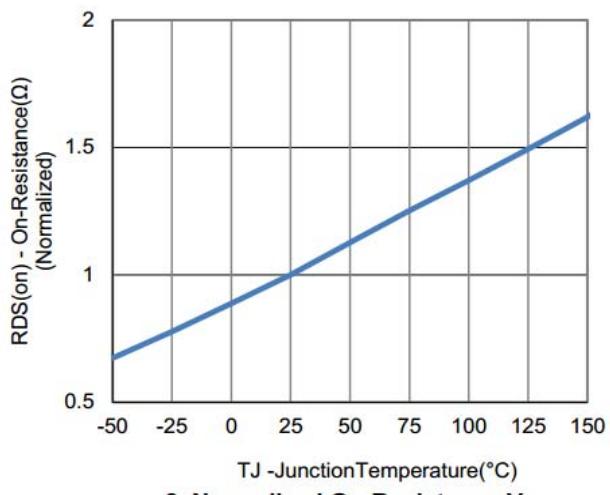


6. Capacitance

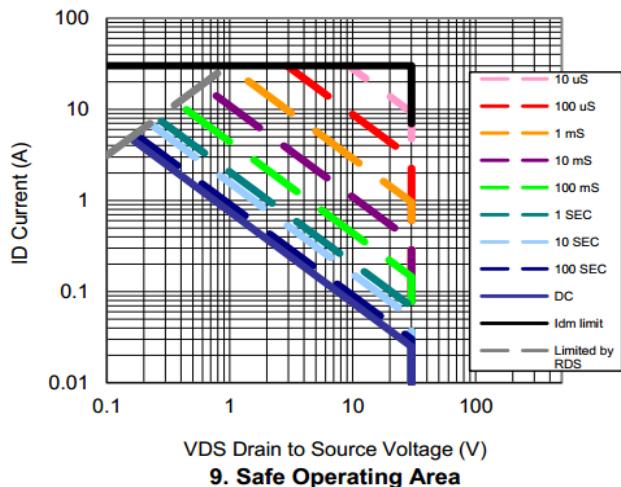
CHARACTERISTIC CURVES



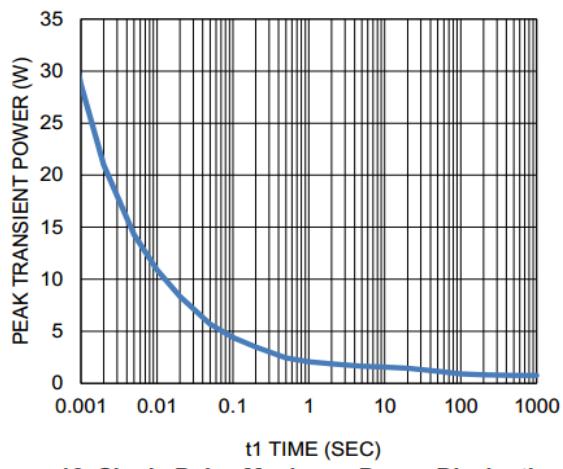
7. Gate Charge



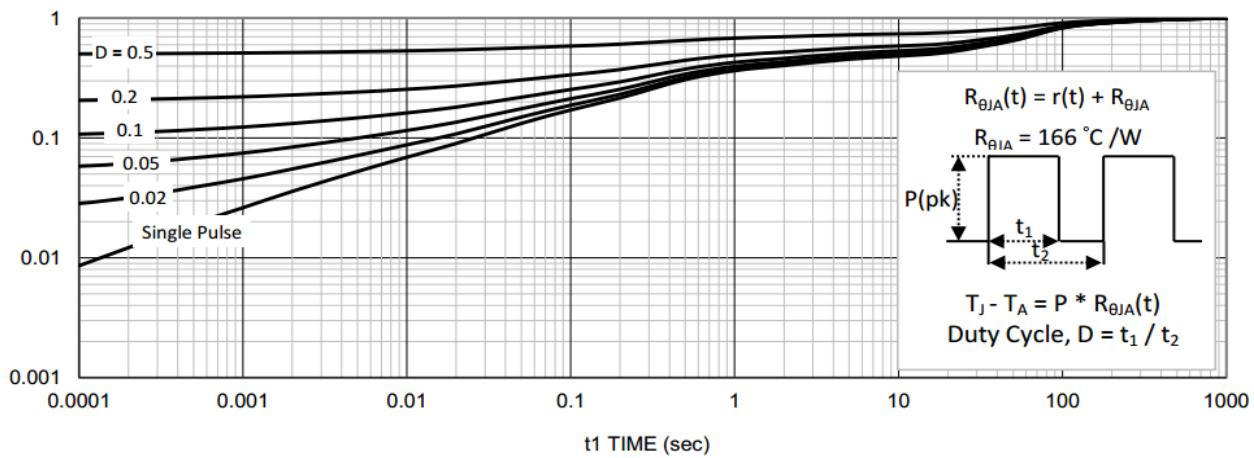
8. Normalized On-Resistance Vs Junction Temperature



9. Safe Operating Area



10. Single Pulse Maximum Power Dissipation



11. Normalized Thermal Transient Junction to Ambient